



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS INTRODUCES NEW HIGH-POWER MAX3
MONITORED BURN-IN SYSTEM WITH JTAG TESTING CAPABILITIES**

FREMONT, CA (July 16, 2001) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of test and burn-in equipment to semiconductor manufacturers, is announcing a high-power version of its MAX3 Dynamic Burn-in System. The new MAX3-HP system offers deep vector capability (24M deep X 4) with monitored burn-in for functionally testing devices that use the JTAG testing methodology, which is now being embedded in higher power components.

“The MAX3-HP dissipates up to 12KW, so it fulfills the needs of our customers who want a lower cost burn-in solution for higher power components such as microprocessors, microcontrollers, and digital signal processors,” said CJ Meurell, president and chief operating officer.

“We designed the new high-power member of the MAX3 family with deep vector capability and output monitoring to take advantage of JTAG and built-in self test (BIST) for testing today’s leading devices,” said Carl Buck, vice president of marketing.

JTAG, an industry-standard testing protocol, enables full functional testing of a device while using as few as four pins. Using BIST techniques, which simplify testing and return pass/fail information directly from the devices, enables the burn-in system to eliminate faulty parts from the testing process earlier. Output testing also helps to achieve targeted reliability, because it ensures that the device is actually getting the proper inputs and receiving the specified burn-in.

The MAX3-HP system delivers burn-in voltages as low as 0.7 volts DC, suitable for ICs with line widths as small as 0.18 microns or smaller. The system also can drive 96 input/output channels—double the number offered by most burn-in systems on the market today—which allows a more complete exercise and test of higher pin-count devices. For mixed signal devices, analog channels are also available. The MAX3-HP system uses the Windows NT operating system, making it easy to support a large network of MAX3-HP systems.



Aehr Test Systems Announces its MAX3-HP, High Power Burn-In System

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Aehr Test is introducing the MAX3-HP system at Semicon West 2001, July 18-20, in the San Jose Convention Center in San Jose, CA, Booth #10727. Anyone desiring additional information regarding Aehr Test's products and services can access the Company's web site, www.aehr.com.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX™, MTX and MAX3 systems and the DiePak® carrier. The FOX is a full wafer contact burn-in and test system. The MTX is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX3 can effectively burn-in and functionally test sophisticated devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding industry growth and customer demand for the Company's products. Actual results may vary from projected results. These risks and uncertainties include economic conditions in Asia and elsewhere, acceptance by customers of the MTX, MAX and DiePak technologies, the Company's development and manufacture of a commercially successful wafer-level burn-in system, and the potential emergence of alternative technologies, which could adversely affect demand for the Company's products in fiscal year 2002. See the Company's 10-K and 10-Q reports filed with the SEC for additional risks affecting the Company.

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